

SLOVENSKI STANDARD

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Visokotokovne preskusne tehnike - Definicije in zahteve za preskusne toke in merilne sisteme (IEC 62475:2010)

High-current test techniques - Definitions and requirements for test currents and measuring systems (IEC 62475:2010)

Hochstrom-Prüftechnik - Begriffe und Anforderungen für Hochstrom-Messungen (IEC 62475:2010)

Techniques des essais à haute intensité - Définitions et exigences relatives aux courants d'essai et systèmes de mesure (CEI 62475:2010)

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EUROPEAN STANDARD
NORME EUROPÉENNE
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**High-current test techniques -
Definitions and requirements for test currents and measuring systems
(IEC 62475:2010)**

Techniques des essais à haute intensité -
Définitions et exigences relatives aux
courants d'essai et systèmes de mesure
(CEI 62475:2010)

Hochstrom-Prüftechnik -
Begriffe und Anforderungen für
Hochstrom-Messungen
(IEC 62475:2010)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 42/278/FDIS, future edition 1 of IEC 62475, prepared by IEC TC 42, High-voltage testing techniques, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62475 on 2010-12-01.

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The following dates were fixed:

- | | | |
|--|-------|------------|
| – latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement | (dop) | 2011-09-01 |
| – latest date by which the national standards conflicting with the EN have to be withdrawn | (dow) | 2013-12-01 |

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 62475:2010 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60076-5:2000	NOTE	Harmonized as EN 60076-5:2000 (not modified).
IEC 60099-4:2004	NOTE	Harmonized as EN 60099-4:2004 (modified).
IEC 60265-1:1998	NOTE	Harmonized as EN 60265-1:1998 (not modified).
IEC 60282-1:2009	NOTE	Harmonized as EN 60282-1:2009 (not modified).
IEC 60947-1:2007	NOTE	Harmonized as EN 60947-1:2007 (not modified).
IEC 60947-2:2006	NOTE	Harmonized as EN 60947-2:2006 (not modified).
IEC 60947-3:2008	NOTE	Harmonized as EN 60947-3:2009 (not modified).
IEC 61000-4-5	NOTE	Harmonized as EN 61000-4-5.
IEC 61083-1:2001	NOTE	Harmonized as EN 61083-1:2001 (not modified).
IEC 61083-2:1996	NOTE	Harmonized as EN 61083-2:1997 (not modified).
IEC 61180-2:1994	NOTE	Harmonized as EN 61180-2:1994 (not modified).
IEC 61230:2008	NOTE	Harmonized as EN 61230:2008 (not modified).
IEC 61643-11	NOTE	Harmonized as EN 61643-11.
IEC 61643-21	NOTE	Harmonized as EN 61643-21.
IEC 62271-1	NOTE	Harmonized as EN 62271-1.
IEC 62271-100:2008	NOTE	Harmonized as EN 62271-100:2009 (not modified).
IEC 62271-101	NOTE	Harmonized as EN 62271-101.
IEC 62271-102:2001	NOTE	Harmonized as EN 62271-102:2002 (not modified).

IEC 62271-103	NOTE	Harmonized as EN 62271-103.
IEC 62271-104	NOTE	Harmonized as EN 62271-104.
IEC 62271-105	NOTE	Harmonized as EN 62271-105.
IEC 62271-110:2009	NOTE	Harmonized as EN 62271-110:2009 (not modified).
IEC 62305-1	NOTE	Harmonized as EN 62305-1.
ISO/IEC 17025:2005	NOTE	Harmonized as EN ISO/IEC 17025:2005 (not modified).

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60051-2	1984	Direct acting indicating analogue electrical measuring instruments and their accessories - Part 2: Special requirements for ammeters and voltmeters	EN 60051-2	1989
IEC 60060-1	2010	High-voltage test techniques - Part 1: General definitions and test requirements	EN 60060-1	2010
IEC 61180-1	-	High-voltage test techniques for low-voltage equipment - Part 1: Definitions, test and procedure requirements	EN 61180-1	-
ISO/IEC Guide 98-3	2008	Uncertainty of measurement - Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)	-	-



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

HIGH-CURRENT TEST TECHNIQUES – DEFINITIONS AND REQUIREMENTS FOR TEST CURRENTS AND MEASURING SYSTEMS

FOREWORD

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International Standard IEC 62475 has been prepared by IEC technical committee 42: High-voltage test techniques.

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FDIS	Report on voting
42/278/FDIS	42/283/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to this specific publication. At this date, the publication will be:

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- withdrawn;
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